

- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ 100% EAS Guaranteed
- ★ Green Device Available

Product Summary



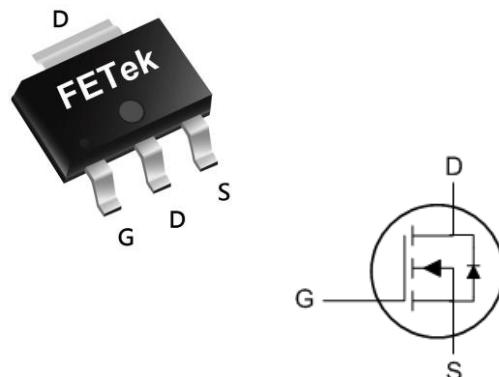
BVDSS	RDS(on)	ID
200V	1.0Ω	1.5A

General Description

The FKL03N20 is the high cell density trenched N-ch MOSFETs, which provide excellent RDS(on) and gate charge for most of the synchronous buck converter applications.

The FKL03N20 meet the RoHS and Green Product requirement, 100% EAS guaranteed with full function reliability approved.

SOT223 Pin Configuration



Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	200	V
V _{GS}	Gate-Source Voltage	±20	V
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	1.5	A
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	1.3	A
I _{DM}	Pulsed Drain Current ²	8	A
EAS	Single Pulse Avalanche Energy ³	8	mJ
I _{AS}	Avalanche Current	4	A
P _D @T _C =25°C	Total Power Dissipation ⁴	4.2	W
T _{STG}	Storage Temperature Range	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	°C

*Drain current limited by maximum junction temperature

Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
R _{θJA}	Thermal Resistance Junction-ambient (Steady State) ¹	---	85	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹	---	30	°C/W



FETek Technology Corp.

FKL03N20

N-ch 200V Fast Switching MOSFETs

Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

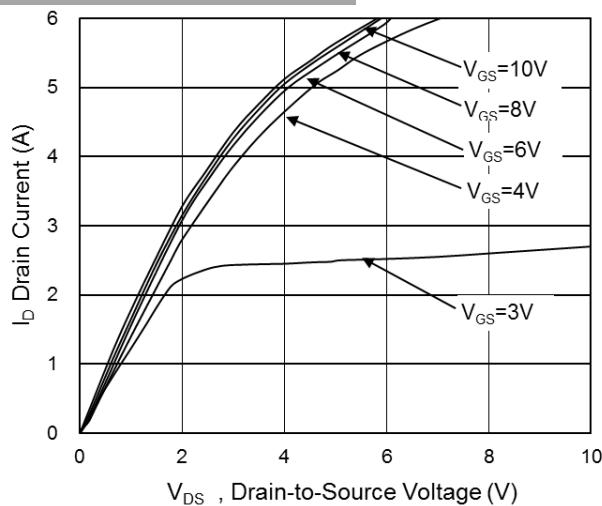
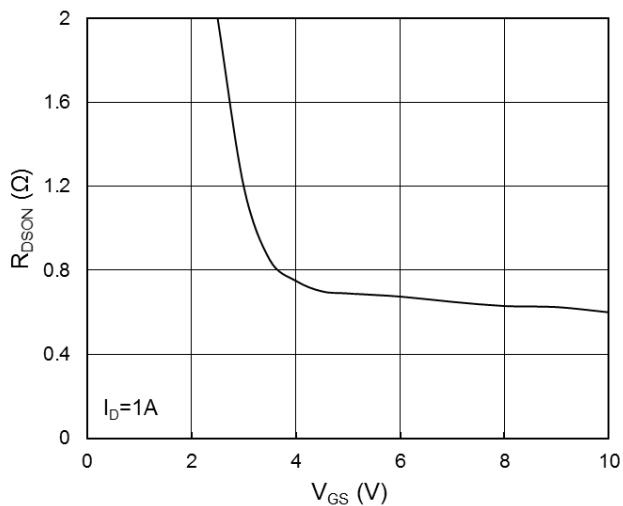
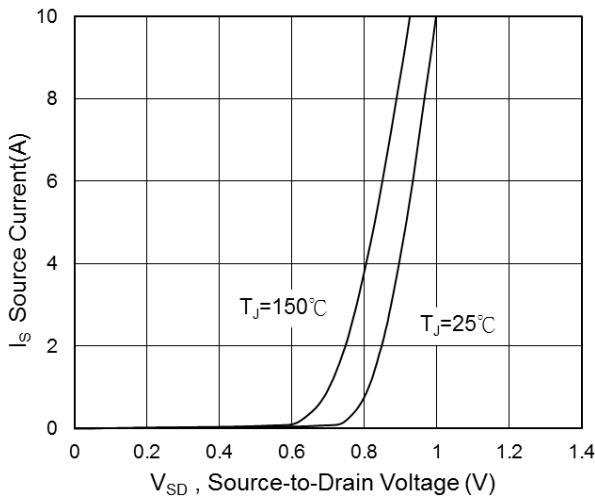
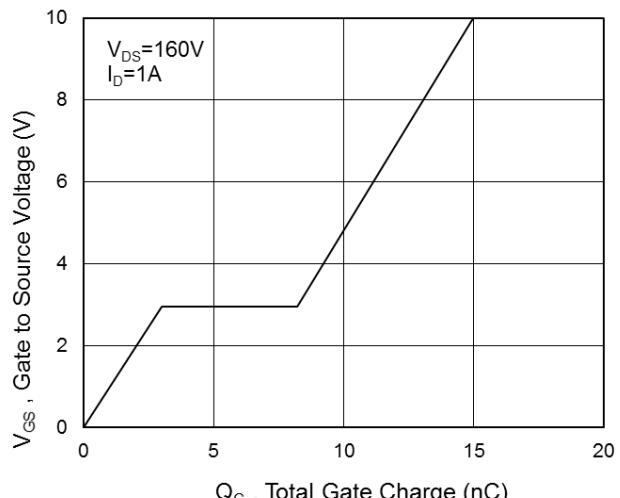
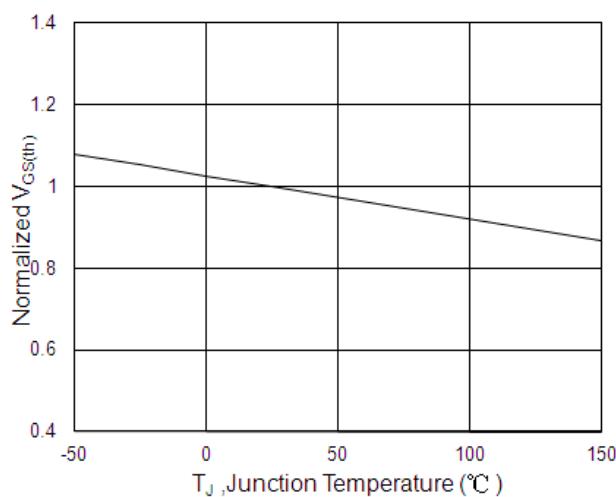
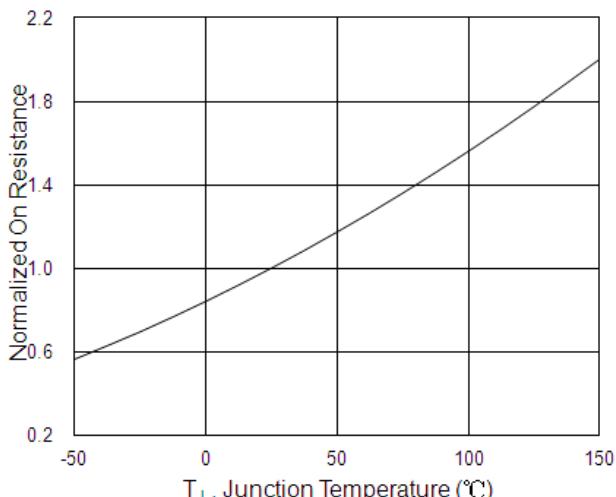
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_D=250\mu\text{A}$	200	---	---	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}$, $I_D=1\text{A}$	---	0.6	1.0	Ω
		$V_{\text{GS}}=4.5\text{V}$, $I_D=1\text{A}$	---	0.7	1.1	Ω
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{GS}}=V_{\text{DS}}$, $I_D=250\mu\text{A}$	1.2	2	3	V
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=200\text{V}$, $V_{\text{GS}}=0\text{V}$, $T_J=25^\circ\text{C}$	---	---	1	μA
I_{GSS}	Gate-Source Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{\text{DS}}=10\text{V}$, $I_D=1\text{A}$	---	10	---	S
Q_g	Total Gate Charge (10V)	$V_{\text{DS}}=160\text{V}$, $V_{\text{GS}}=10\text{V}$, $I_D=1\text{A}$	---	15	---	nC
Q_{gs}	Gate-Source Charge		---	3.0	---	
Q_{gd}	Gate-Drain Charge		---	5.2	---	
$T_{\text{d(on)}}$	Turn-On Delay Time	$V_{\text{DD}}=100\text{V}$, $V_{\text{GS}}=10\text{V}$, $R_G=3\Omega$, $I_D=1\text{A}$	---	22	---	ns
T_r	Rise Time		---	34	---	
$T_{\text{d(off)}}$	Turn-Off Delay Time		---	45	---	
T_f	Fall Time		---	11	---	
C_{iss}	Input Capacitance	$V_{\text{DS}}=25\text{V}$, $V_{\text{GS}}=0\text{V}$, $F=1\text{MHz}$	---	900	---	pF
C_{oss}	Output Capacitance		---	130	---	
C_{rss}	Reverse Transfer Capacitance		---	4.6	---	

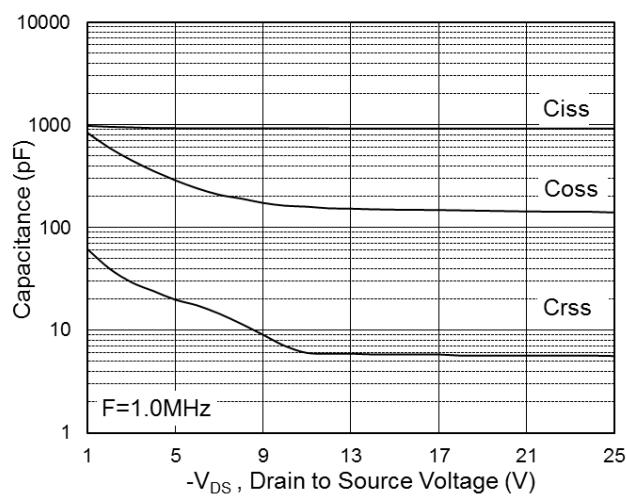
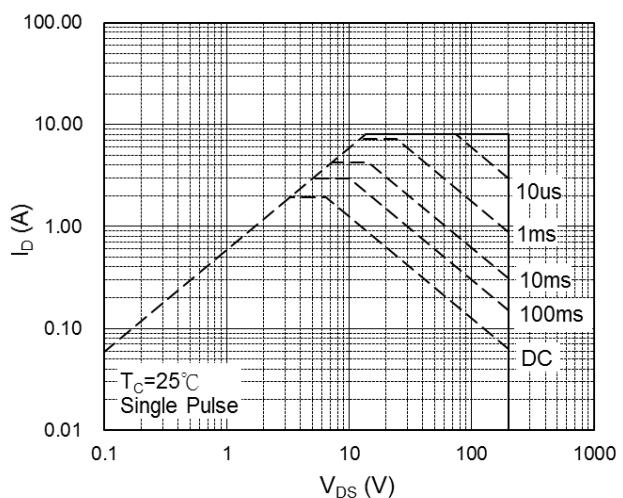
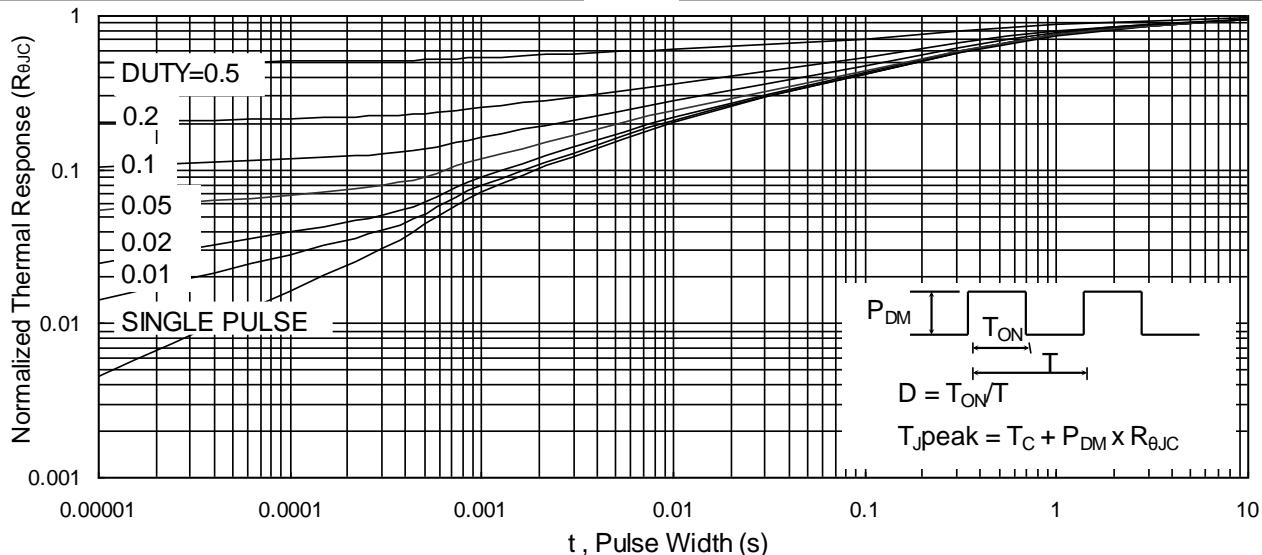
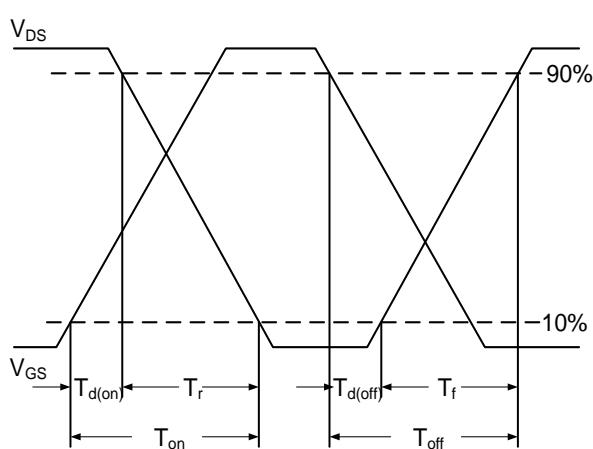
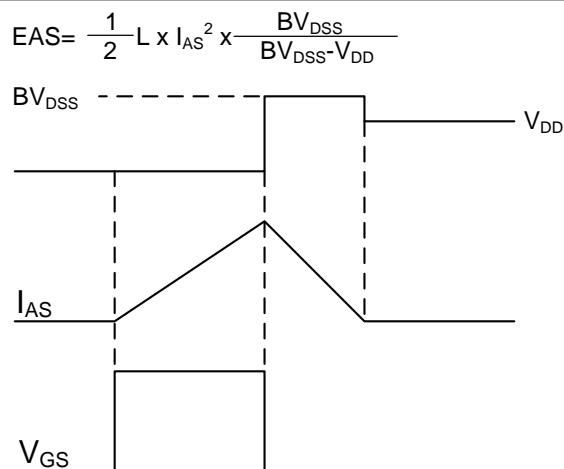
Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current ^{1,6}	$V_G=V_D=0\text{V}$, Force Current	---	---	1	A
V_{SD}	Diode Forward Voltage ²	$V_{\text{GS}}=0\text{V}$, $I_s=1\text{A}$, $T_J=25^\circ\text{C}$	---	---	1	V
t_{rr}	Reverse Recovery Time	$I_F=1\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$,	---	85	---	nS
Q_{rr}	Reverse Recovery Charge	$T_J=25^\circ\text{C}$	---	257	---	nC

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{\text{DD}}=50\text{V}$, $V_{\text{GS}}=10\text{V}$, $L=1\text{mH}$, $I_{\text{AS}}=4\text{A}$
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The Min. value is 100% EAS tested guarantee.
- 6.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

Fig.1 Typical Output Characteristics

Fig.2 On-Resistance vs. G-S Voltage

Fig.3 Forward Characteristics of Reverse

Fig.4 Gate-Charge Characteristics

Fig.5 $V_{GS(th)}$ vs. T_J

Fig.6 Normalized $R_{DS(on)}$ vs. T_J


Fig.7 Capacitance

Fig.8 Safe Operating Area

Fig.9 Normalized Maximum Transient Thermal Impedance

Fig.10 Switching Time Waveform

Fig.11 Unclamped Inductive Switching Waveform

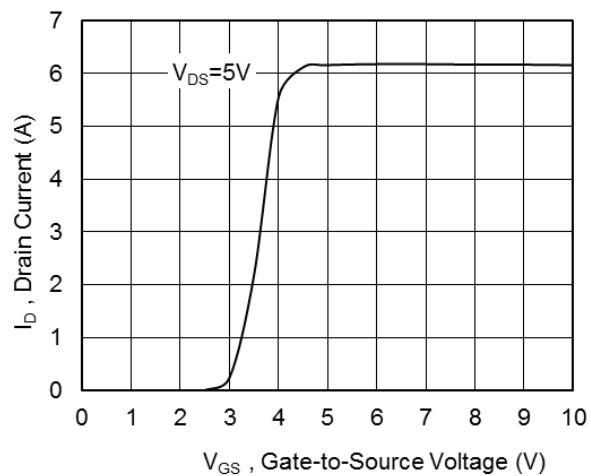


Fig.11 Transfer Characteristics